

100314

Low Power Quint Differential Line Receiver

General Description

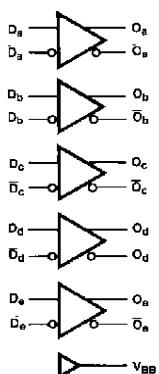
The 100314 is a monolithic quint differential line receiver with emitter-follower outputs. An internal reference supply (V_{BB}) is available for single-ended reception. When used in single-ended operation the apparent input threshold of the true inputs is 25 mV to 30 mV higher (positive) than the threshold of the complementary inputs. Unlike other F100K ECL devices, the inputs do not have input pull-down resistors.

Active current sources provide common-mode rejection of 1.0V in either the positive or negative direction. A defined output state exists if both inverting and non-inverting inputs are at the same potential between V_{EE} and V_{CC} . The defined state is logic HIGH on the \bar{O}_a - \bar{O}_e outputs.

Features

- 35% power reduction of the 100114
- 2000V ESD protection
- Pin/function compatible with 100114
- Voltage compensated operating range = -4.2V to -5.7V
- Available to MIL-STD-883
- Available to industrial grade temperature range

Logic Symbol

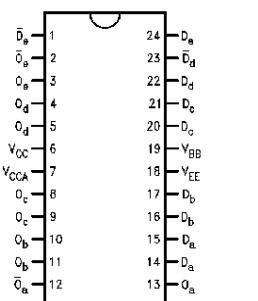


TL/F/10260-1

Pin Names	Description
D_a - D_e	Data Inputs
\bar{D}_a - \bar{D}_e	Inverting Data Inputs
O_a - O_e	Data Outputs
\bar{O}_a - \bar{O}_e	Complementary Data Outputs

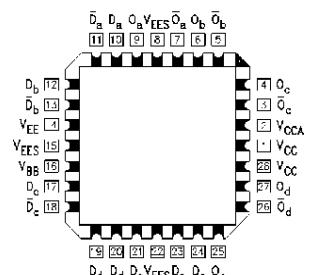
Connection Diagrams

24-Pin DIP/SOIC



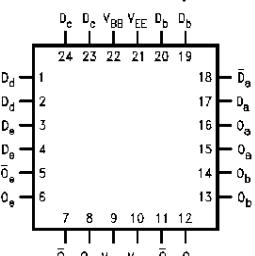
TL/F/10260-2

28-Pin PCC



TL/F/10260-4

24-Pin Quad Cerpak



TL/F/10260-3

Absolute Maximum Ratings

Above which the useful life may be impaired (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature (T_{STG}) -65°C to $+150^{\circ}\text{C}$

Maximum Junction Temperature (T_J)
Ceramic $+175^{\circ}\text{C}$
Plastic $+150^{\circ}\text{C}$

Pin Potential to Ground Pin (V_{EE}) -7.0V to $+0.5\text{V}$

Input Voltage (DC) V_{EE} to $+0.5\text{V}$

Output Current (DC Output HIGH) -50 mA

ESD (Note 2) $\geq 2000\text{V}$

Note 1: Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: ESD testing conforms to MIL-STD-883, Method 3015.

Recommended Operating Conditions

Case Temperature (T_C)

0°C to $+85^{\circ}\text{C}$
 -40°C to $+85^{\circ}\text{C}$
 -55°C to $+125^{\circ}\text{C}$

Supply Voltage (V_{EE})

-5.7V to -4.2V

Commercial Version

DC Electrical Characteristics

$V_{EE} = -4.2\text{V}$ to -5.7V , $V_{CC} = V_{CCA} = \text{GND}$, $T_C = 0^{\circ}\text{C}$ to $+85^{\circ}\text{C}$ (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	Conditions		
V_{OH}	Output HIGH Voltage	-1025	-955	-870	mV	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to -2.0V	
V_{OL}	Output LOW Voltage	-1830	-1705	-1620	mV			
V_{OHC}	Output HIGH Voltage	-1035			mV	$V_{IN} = V_{IH}$ or V_{IL} (Max)	Loading with 50Ω to -2.0V	
V_{OLC}	Output LOW Voltage			-1610	mV			
V_{BB}	Output Reference Voltage	-1380	-1320	-1260	mV	$I_{VBB} = -250\ \mu\text{A}$		
V_{DIFF}	Input Voltage Differential	150			mV	Required for Full Output Swing		
V_{CM}	Common Mode Voltage	$V_{CC} - 2.0$		$V_{CC} - 0.5$	V			
V_{IH}	Single-Ended Input High Voltage	-1110		-870	mV	Guaranteed HIGH Signal for All Inputs (with one input tied to V_{BB}) V_{BB} (Max) + V_{DIFF}		
V_{IL}	Single-Ended Input Low Voltage	-1830		-1530	mV	Guaranteed LOW Signal for All Inputs (with one input tied to V_{BB}) V_{BB} (Min) - V_{DIFF}		
I_{IL}	Input LOW Current	0.50			μA	$V_{IN} = V_{IL}$ (Min)		
I_{IH}	Input HIGH Current			240	μA	$V_{IN} = V_{IH}$ (Max), $D_a - D_e = V_{BB}$, $\bar{D}_a - \bar{D}_e = V_{IL}$ (Min)		
I_{CBO}	Input Leakage Current	-10			μA	$V_{IN} = V_{EE}$, $D_a - D_e = V_{BB}$, $\bar{D}_a - \bar{D}_e = V_{IL}$ (Min)		
I_{EE}	Power Supply Current	-60		-30	mA	$D_a - D_e = V_{BB}$, $\bar{D}_a - \bar{D}_e = V_{IL}$ (Min)		

Note 3: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

Commercial Version (Continued)

DIP AC Electrical Characteristics $V_{EE} = -4.2V \text{ to } -5.7V, V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
f_{MAXFS}	Toggle Frequency (Full Swing)	250		250		250		MHz	(Note 2)
f_{MAXRS}	Toggle Frequency (Reduced Swing)	700		700		700		MHz	(Note 3)
t_{PLH} t_{PHL}	Propagation Delay Data to Output	0.65	1.90	0.65	2.00	0.70	2.00	ns	Figures 1 and 2
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.35	1.20	0.35	1.20	0.35	1.20	ns	

SOIC, PCC and Cerpak AC Electrical Characteristics

$V_{EE} = -4.2V \text{ to } -5.7V, V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
f_{MAXFS}	Toggle Frequency (Full Swing)	250		250		250		MHz	(Note 2)
f_{MAXRS}	Toggle Frequency (Reduced Swing)	700		700		700		MHz	(Note 3)
t_{PLH} t_{PHL}	Propagation Delay Data to Output	0.65	1.70	0.65	1.80	0.70	1.80	ns	Figures 1 and 2
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	
t_{PLH} t_{PHL}	Propagation Delay Data to Output	0.70	1.50	0.80	1.60	0.90	1.80	ns	PCC only
t_{OSHL}	Maximum Skew Common Edge Output-to-Output Variation Data to Output Path		280		280		280	ps	PCC only (Notes 1 and 4)
t_{OSLH}	Maximum Skew Common Edge Output-to-Output Variation Data to Output Path		330		330		330	ps	PCC only (Notes 1 and 4)
t_{OST}	Maximum Skew Opposite Edge Output-to-Output Variation Data to Output Path		330		330		330	ps	PCC only (Notes 1 and 4)
t_{PS}	Maximum Skew Pin (Signal) Transition Variation Data to Output Path		320		320		320	ps	PCC only (Notes 1 and 4)

Note 1: Output-to-Output Skew is defined as the absolute value of the difference between the actual propagation delay for any outputs within the same packaged device. The specifications apply to any outputs switching in the same direction either HIGH to LOW (t_{OSHL}), or LOW to HIGH (t_{OSLH}), or in opposite directions both HL and LH (t_{OST}). Parameters t_{OST} and t_{PS} guaranteed by design.

Note 2: Maximum toggle frequency at which V_{OH} and V_{OL} DC specifications are maintained.

Note 3: Maximum toggle frequency at which outputs maintain 150 mV swing.

Note 4: All skews calculated using input crossing point to output crossing point propagation delays.

Industrial Version

PCC DC Electrical Characteristics

$V_{EE} = -4.2V \text{ to } -5.7V, V_{CC} = V_{CCA} = GND, T_C = -40^\circ C \text{ to } +85^\circ C$ (Note 1)

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = 0^\circ C \text{ to } +85^\circ C$		Units	Conditions	
		Min	Max	Min	Max			
V_{OH}	Output HIGH Voltage	-1085	-870	-1025	-870	mV	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to -2.0V
V_{OL}	Output LOW Voltage	-1830	-1575	-1830	-1620	mV		

Industrial Version (Continued)

PCC DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -40^\circ C$ to $+85^\circ C$ (Note 1) (Continued)

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = 0^\circ C$ to $+85^\circ C$		Units	Conditions	
		Min	Max	Min	Max			
V_{OHC}	Output HIGH Voltage	-1095		-1035		mV	$V_{IN} = V_{IH}$ or V_{IL} (Min)	Loading with 50Ω to $-2.0V$
V_{OLC}	Output LOW Voltage	-1565		-1610		mV		
V_{BB}	Output Reference Voltage	-1395	-1255	-1380	-1260	mV	$I_{VBB} = -250 \mu A$	
V_{DIFF}	Input Voltage Differential	150		150		mV	Required for Full Output Swing	
V_{CM}	Common Mode Voltage	$V_{CC} - 2.0$	$V_{CC} - 0.5$	$V_{CC} - 2.0$	$V_{CC} - 0.5$	V		
V_{IH}	Single-Ended Input High Voltage	-1115	-870	-1110	-870	mV	Guaranteed HIGH Signal for All Inputs (with one input tied to V_{BB}) V_{BB} (Max) + V_{DIFF}	
V_{IL}	Single-Ended Input Low Voltage	-1830	-1535	-1830	-1530	mV	Guaranteed LOW Signal for All Inputs (with one input tied to V_{BB}) V_{BB} (Min) - V_{DIFF}	
I_{IL}	Input LOW Current	0.50		0.50		μA	$V_{IN} = V_{IL}$ (Min)	
I_{IH}	Input HIGH Current	240		240		μA	$V_{IN} = V_{IH}$ (Max), $D_a - D_e = V_{BB}$, $D_a - D_e = V_{IL}$ (Min)	
I_{CBO}	Input Leakage Current	-10		-10		μA	$V_{IN} = V_{EE}$, $D_a - D_e = V_{BB}$, $D_a - D_e = V_{IL}$ (Min)	
I_{EE}	Power Supply Current	-60	-30	-60	-30	mA	$D_a - D_e = V_{BB}$, $\bar{D}_a - \bar{D}_e = V_{IL}$ (Min)	

Note 1: The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

PCC AC Electrical Characteristics $V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
f_{MAXFS}	Toggle Frequency (Full Swing)	250		250		250		MHz	(Note 2)
f_{MAXRS}	Toggle Frequency (Reduced Swing)	700		700		700		MHz	(Note 3)
t_{PLH} t_{PHL}	Propagation Delay Data to Output	0.65	1.70	0.65	1.80	0.70	1.80	ns	Figures 1 and 2
t_{TLH} t_{THL}	Transition Time 20% to 80%, 80% to 20%	0.20	1.40	0.35	1.10	0.35	1.10	ns	

Military Version

DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^\circ C$ to $+125^\circ C$ (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	T_C	Conditions		Notes
V_{OH}	Output HIGH Voltage	-1025		-870	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to $-2.0V$	1, 2, 3
		-1085		-870	mV	-55°C			
V_{OL}	Output LOW Voltage	-1830		-1620	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to $-2.0V$	1, 2, 3
		-1830		-1555	mV	-55°C			

Military Version (Continued)

DC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$, $T_C = -55^{\circ}C$ to $+125^{\circ}C$ (Note 3) (Continued)

Symbol	Parameter	Min	Typ	Max	Units	T_C	Conditions		Notes
V_{OHC}	Output HIGH Voltage	-1035			mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to $-2.0V$	1, 2, 3
		-1085			mV	$-55^{\circ}C$			
V_{OLC}	Output LOW Voltage			-1610	mV	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Max) or V_{IL} (Min)	Loading with 50Ω to $-2.0V$	1, 2, 3
				-1555	mV	$-55^{\circ}C$			
V_{BB}	Output Reference Voltage			-1260	mV	$0^{\circ}C$ to $+125^{\circ}C$	$I_{VBB} = 0 \mu A$, $V_{EE} = 4.2V$	1, 2, 3	
		-1380		-1260	mV	$0^{\circ}C$ to $+125^{\circ}C$	$I_{VBB} = -250 \mu A$, $V_{EE} = -5.7V$		
		-1396			mV	$-55^{\circ}C$	$I_{VBB} = -350 \mu A$, $V_{EE} = -5.7V$		
V_{DIFF}	Input Voltage Differential	150			mV	$-55^{\circ}C$ to $+125^{\circ}C$	Required for Full Output Swing	1, 2, 3	
V_{CM}	Common Mode Voltage	$V_{CC} - 2.0$		$V_{CC} - 0.5$	V	$-55^{\circ}C$ to $+125^{\circ}C$		1, 2, 3	
V_{IH}	Single-Ended Input High Voltage	-1165		-870	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed HIGH Signal for All Inputs (with \bar{D}_n tied to V_{BB})	1, 2, 3, 4	
V_{IL}	Single-Ended Input Low Voltage	-1830		-1475	mV	$-55^{\circ}C$ to $+125^{\circ}C$	Guaranteed LOW Signal for All Inputs (with \bar{D}_n tied to V_{BB})	1, 2, 3, 4	
I_{IH}	Input HIGH Current			50	μA	$0^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{IH}$ (Max), $D_a - D_e = V_{BB}$, $\bar{D}_a - \bar{D}_e = V_{IL}$ (Min)	1, 2, 3	
				70	μA	$-55^{\circ}C$			
I_{CBO}	Input Leakage Current	-10			μA	$-55^{\circ}C$ to $+125^{\circ}C$	$V_{IN} = V_{EE}$, $D_a - D_e = V_{BB}$, $\bar{D}_a - \bar{D}_e = V_{IL}$ (Min)	1, 2, 3	
I_{EE}	Power Supply Current	-65		-25	mA	$-55^{\circ}C$ to $+125^{\circ}C$	$D_a - D_e = V_{BB}$, $\bar{D}_a - \bar{D}_e = V_{IL}$ (Min)	1, 2, 3	

Note 1: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^{\circ}C$), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 2: Screen tested 100% on each device at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups 1, 2, 3, 7, and 8.

Note 3: Sample tested (Method 5005, Table I) on each manufactured lot at $-55^{\circ}C$, $+25^{\circ}C$, and $+125^{\circ}C$, Subgroups A1, 2, 3, 7, and 8.

Note 4: Guaranteed by applying specified input condition and testing V_{OH}/V_{OL} .

AC Electrical Characteristics

$V_{EE} = -4.2V$ to $-5.7V$, $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^{\circ}C$		$T_C = +25^{\circ}C$		$T_C = +125^{\circ}C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
t_{PLH} t_{PHL}	Propagation Delay Data to Output	0.40	2.30	0.60	2.20	0.60	2.70	ns	<i>Figures 1 and 2</i>	1, 2, 3
		0.20	1.40	0.20	1.40	0.20	1.40	ns		

Note 1: F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals $-55^{\circ}C$), then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

Note 2: Screen tested 100% on each device at $+25^{\circ}C$ temperature only, Subgroup A9.

Note 3: Sample tested (Method 5005, Table I) on each manufactured lot at $+25^{\circ}C$, Subgroup A9, and at $+125^{\circ}C$ and $-55^{\circ}C$ temperatures, Subgroups A10 and A11.

Note 4: Not tested at $+25^{\circ}C$, $+125^{\circ}C$ and $-55^{\circ}C$ temperature (design characterization data).

Test Circuit

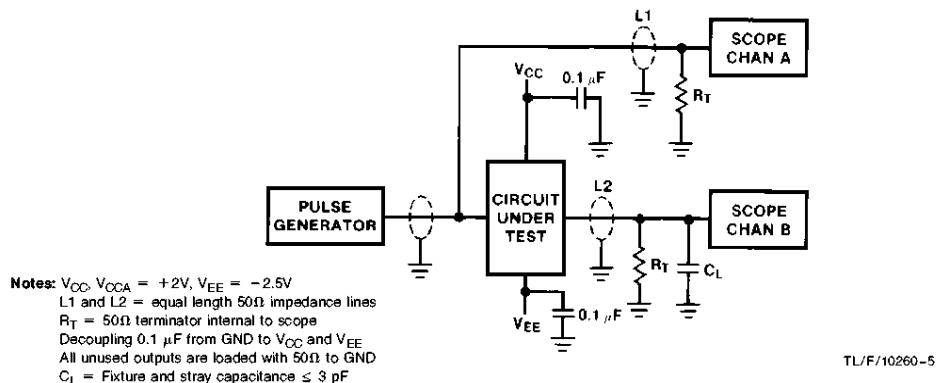


FIGURE 1. AC Test Circuit

Switching Waveforms

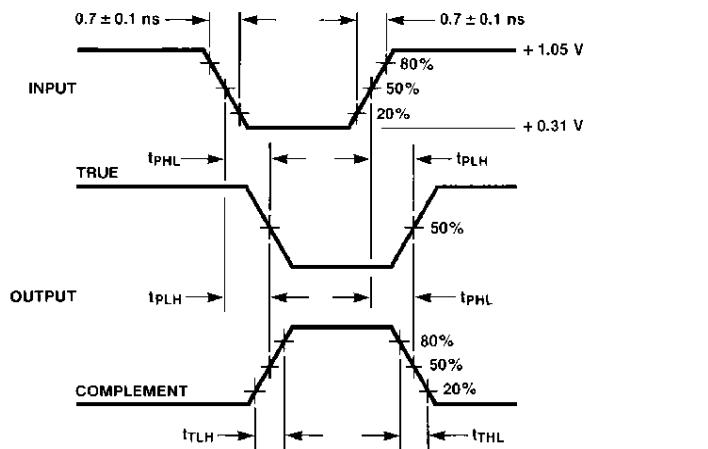


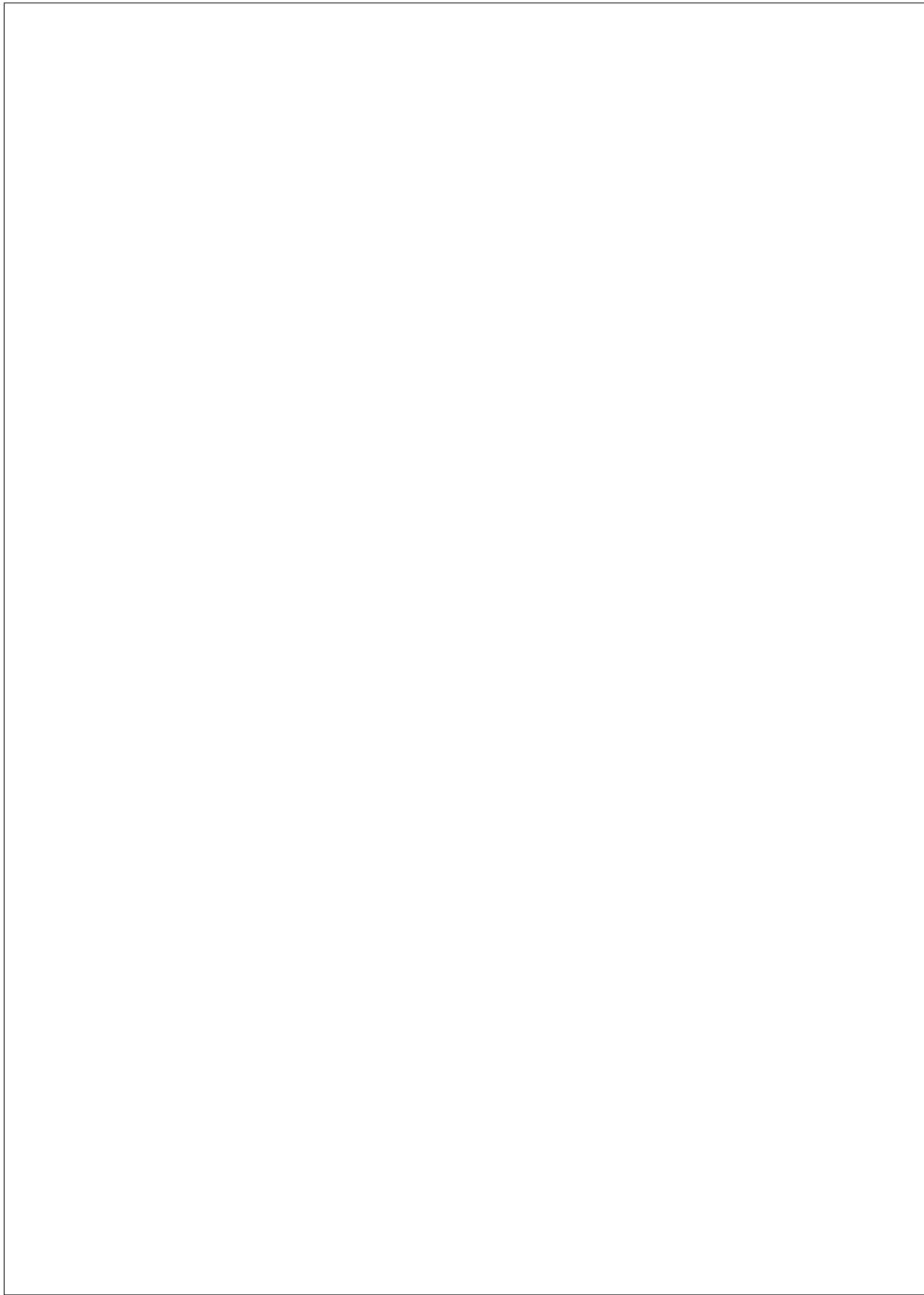
FIGURE 2. Propagation Delay and Transition Times

Ordering Information

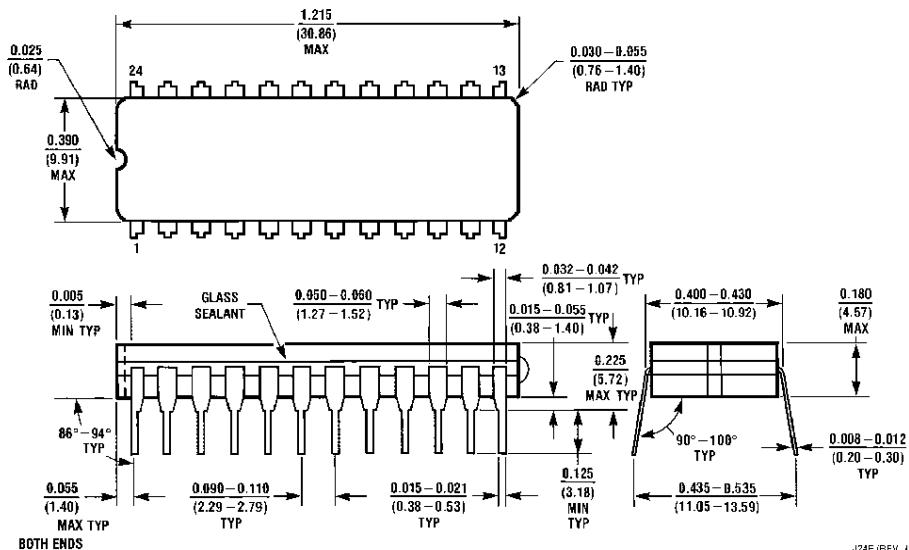
The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:

Device Type (Basic)	100314	D	C	QB	Special Variation QB = Military grade device with environmental and burn-in processing
Package Code					Temperature Range C = Commercial (0°C to $+85^\circ\text{C}$) I = Industrial (-40°C to $+85^\circ\text{C}$) (PCC only) M = Military (-55°C to $+125^\circ\text{C}$)

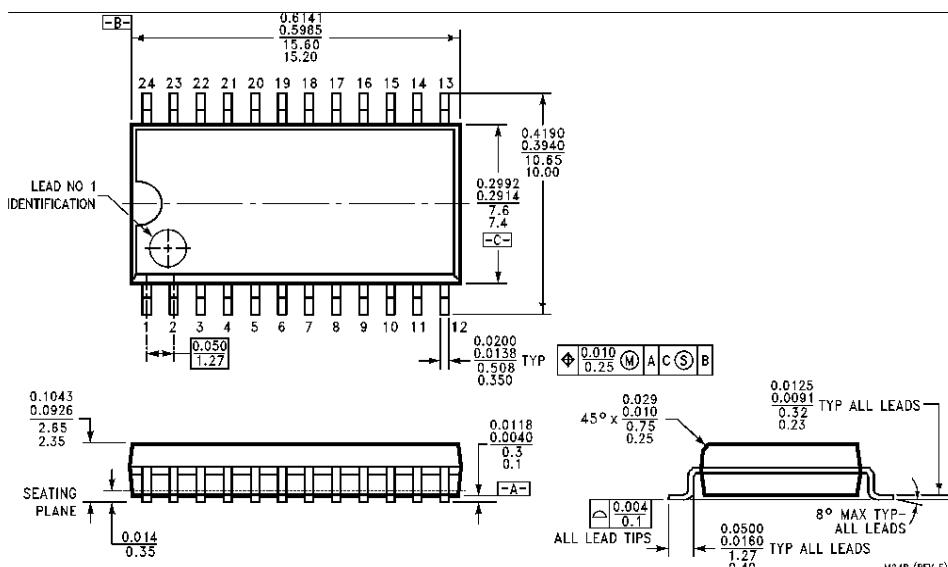
D = Ceramic DIP
F = Quad Cerpak
Q = Plastic Leaded Chip Carrier (PCC)
P = Plastic DIP
S = Small Outline (SOIC)



Physical Dimensions inches (millimeters)

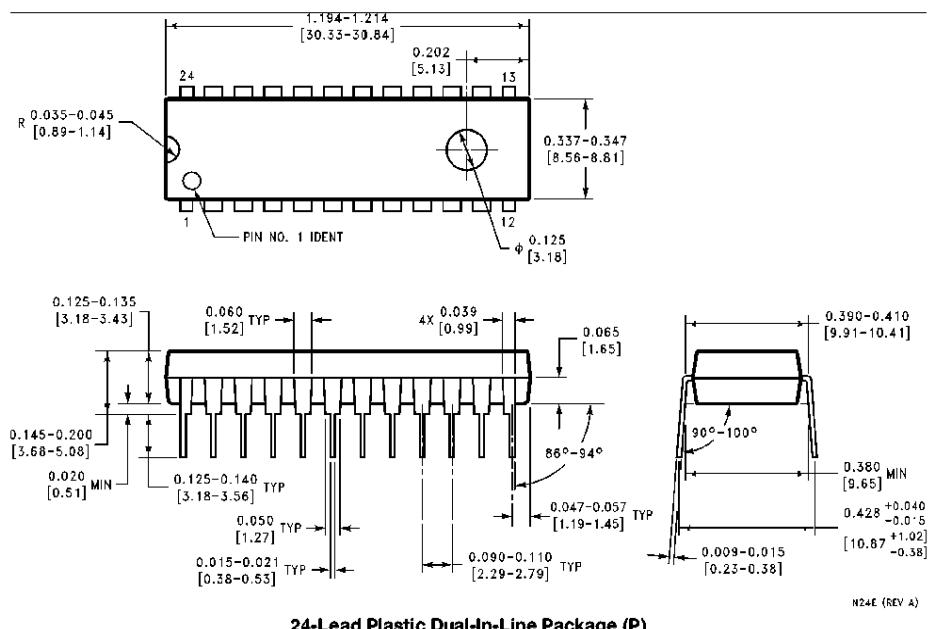


**24-Lead Ceramic Dual-In-Line Package (0.400" Wide) (D)
NS Package Number J24E**



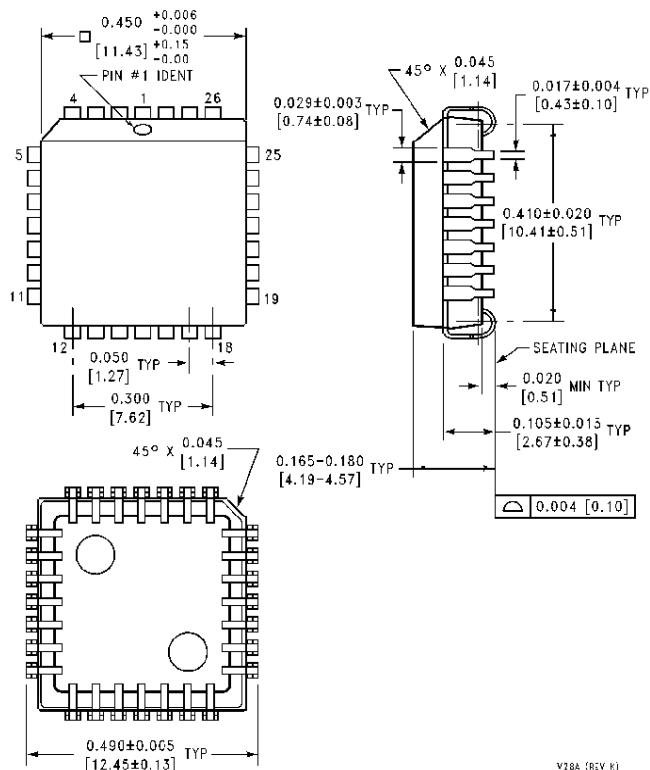
**24-Lead Molded Package (0.300" Wide) (S)
NS Package Number M24B**

Physical Dimensions inches (millimeters) (Continued)



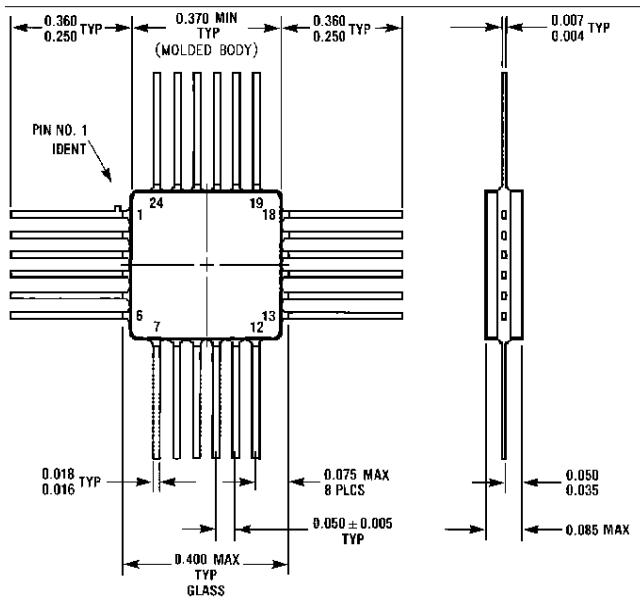
24-Lead Plastic Dual-In-Line Package (P)
NS Package Number N24E

28-Lead Plastic Chip Carrier (Q)
NS Package Number V28A



Physical Dimensions inches (millimeters) (Continued)

Lit. # 114905



W24B (REV D)

**24-Lead Quad Cerpak (F)
NS Package Number W24B**

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



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